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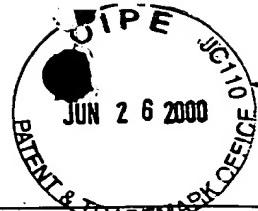
Form PTO-1449 (Substitute)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01000US0 SRM	Serial/Patent Number 09/465,592
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use several sheets if necessary)</i>		Applicant/Patent Owner Culver, et al.	
		Filing/Issue Date December 17, 1999	Group Art Unit 2824 2653

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
KC	1	4,575,822	3/11/86	Quate	/	/	
KC	2	4,829,507	3/9/89	Kazan et al.	/	/	
KC	3	4,916,688	4/10/90	Foster et al.	/	/	
KC	4	4,945,515	7/31/90	Ooumi et al.	/	/	
KC	5	4,962,480	10/9/90	Ooumi et al.	/	/	
KC	6	4,987,312	1/22/91	Eigler	JUN 30 2000	TECHNOLOGY CENTER 2800	/
KC	7	5,038,322	8/6/91	Van Loenen	/	/	
KC	8	5,051,977	9/24/91	Goldberg	/	/	
KC	9	5,091,880	2/25/92	Isono et al.	/	/	
KC	10	5,144,148	9/1/92	Eigler	/	/	
KC	11	5,187,367	2/16/93	Miyazaki et al.	/	/	
KC	12	5,216,631	6/1/93	Sliwa, Jr.	/	/	
KC	13	5,251,200	10/5/93	Hatanaka et al.	/	/	
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KC	19	6,038,916	3/21/00	Cleveland et al.	/	/	

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Subclass	Trans- lation Yes No



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OTHER DOCUMENTS (Include Author, Title, Date, Pertinent pages, etc.)

1c	20	<i>Ion irradiation effects on graphite with the scanning tunneling microscope; T.C. Shen, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1376-1379</i>
1c	21	<i>Tailoring nanostructures with a scanning tunneling microscope; U.Staufer, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1389-1393</i>
1c	22	<i>Gold deposition from a scanning tunneling microscope tip; H.J. Mamin, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1398-1402</i>
1c	23	<i>Pattern generation on semiconductor surfaces by a scanning tunneling microscope operating in air; J.A. Dagata, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1384-1388</i>
1c	24	<i>Nanometer-scale hole formation on graphite using a scanning tunneling microscope; T.R. Albrecht, et al.; Appl.Phys.Lett., Vol.55, No.17, 23 October 1989; pp.1727-1729</i>
1c	25	<i>Has Japan Begun to Move Toward Atomic Level Material Processing?; M.Aono; Science, Vol. 258; 23 October 1992</i>
Examiner <u>Ciara Chen</u>		Date Considered <u>8/3/02</u>

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*1 = Copy not submitted because it was submitted in prior application SN /_____, filed _____, 19_____.
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Form PTO-1449 (Substitute)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-1000US0 SRM	Serial/Patent Number 09/465,592
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use several sheets if necessary)</i>		Applicant/Patent Owner Joanne P. Culver, et al.	
		Filing/Issue Date December 17, 1999	Group Art Unit 2824 <i>2653</i>

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PATENT & TRADEMARK OFFICE

U.S. PATENTS

Examiner Initial	Patent Number	Issue Date	Inventor	Class	Subclass	Filing Date
<i>lc</i>	1 5,043,578	8/27/1991	Guethner et al.	250	307	
<i>kc</i>	2 5,260,567	11/9/1993	Kuroda et al.	250	359.1	/
<i>loc</i>	3 5,323,375	6/21/1994	Ihara et al.	369	126	/

U.S. PATENT PUBLICATIONS

Examiner Initial	Patent Application Publication Number	Publication Date	Applicant
			<i>TO 2600 FEB 21 2001 MAIL ROOM</i>

PENDING U.S. PATENT APPLICATIONS

Examiner Initial	Application Number	Filing Date	Inventor	Petition to Expunge? Yes No
				<i>NO</i>

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Publication Date	Country	Class	Subclass	Trans-lation Yes No

OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)

<i>lc</i>	4	PCT Written Opinion mailed December 18, 2000, International Application No. PCT/US99/30326, filed December 20, 1999

Examiner *Kim Chin* Date Considered *9/3/02*

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